### **Power MOSFET**

## 30 V, 7.0 A, Single N-Channel, TSOP-6

### **Features**

- Low R<sub>DS(on)</sub>
- Low Gate Charge
- NV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable
- Pb-Free Package is Available

### **Applications**

- Load Switch
- Notebook PC
- Desktop PC

### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Rating			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	30	V
Gate-to-Source Voltage	Gate-to-Source Voltage			±20	V
Continuous Drain	Steady	T <sub>A</sub> = 25°C	I <sub>D</sub>	5.0	Α
Current (Note 1)	State	T <sub>A</sub> = 85°C		3.6	
	t ≤ 10 s	T <sub>A</sub> = 25°C		7.0	
Power Dissipation (Note 1)	Steady State	T <sub>A</sub> = 25°C	P <sub>D</sub>	1.0	W
	t ≤ 10 s			2.0	
Continuous Drain	Steady	T <sub>A</sub> = 25°C	Ι <sub>D</sub>	3.5	Α
Current (Note 2)	State	T <sub>A</sub> = 85°C	1	2.5	
Power Dissipation (Note 2)		T <sub>A</sub> = 25°C	P <sub>D</sub>	0.5	W
Pulsed Drain Current	$t_p = 10 \ \mu s, \ V_{GS} = 10 V$		$I_{DM}$	45	Α
Pulsed Drain Current	$t_p = 30 \mu s, V_{GS} = 5V$		Ι <sub>D</sub>	30	Α
Operating Junction and Storage Temperature		T <sub>J</sub> , T <sub>STG</sub>	–55 to 150	°C	
Source Current (Body Diode)		Is	2.0	Α	
	Single Pulse Drain-to-Source Avalanche Energy (V <sub>DD</sub> = 30 V, I <sub>L</sub> = 10.4 A, V <sub>GS</sub> = 10 V, L = 1.0 mH, R <sub>G</sub> = 25 $\Omega$ )		EAS	54	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE RATINGS

Rating	Symbol	Max	Unit
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	125	°C/W
Junction-to-Ambient – t ≤ 10 s (Note 1)	$R_{\theta JA}$	62.5	
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	248	

- 1. Surface-mounted on FR4 board using 1 inch sq pad size (Cu area = 1.127 in sq [1 oz] including traces).
- Surface-mounted on FR4 board using the minimum recommended pad size (Cu area = 0.0773 in sq).

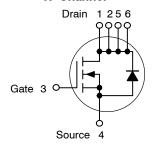


### ON Semiconductor®

### http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> TYP	I <sub>D</sub> MAX
20.14	21.5 mΩ @ 10 V	7.0.4
30 V	30 mΩ @ 4.5 V	7.0 A

#### N-Channel





TSOP-6 CASE 318G STYLE 1



**MARKING** 

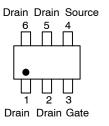
XX = Device Code

M = Date Code

Pb-Free Package

(Note: Microdot may be in either location)

#### **PIN ASSIGNMENT**



### **ORDERING INFORMATION**

See detailed ordering and shipping information ion page 5 of this data sheet.

### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted)

Characteristic	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				18.4		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	$T_J = 25^{\circ}C$			1.0	μΑ
		$V_{GS} = 0 V$ , $V_{DS} = 24 V$	T <sub>J</sub> = 125°C			10	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>0</sub>				±100	nA
ON CHARACTERISTICS (Note 3)						,	
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{I}$	<sub>O</sub> = 250 μA	1.0		3.0	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.7		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V,	I <sub>D</sub> = 7.0 A		21.5	25	mΩ
		V <sub>GS</sub> = 4.5 V,	I <sub>D</sub> = 6.0 A		30	35	
Forward Transconductance	9FS	V <sub>DS</sub> = 10 V,	I <sub>D</sub> = 7.0 A		30		S
CHARGES, CAPACITANCES AND GATE RE	ESISTANCE						
Input Capacitance	C <sub>ISS</sub>				560		pF
Output Capacitance	C <sub>OSS</sub>	$V_{GS} = 0 \text{ V, f} = V_{DS} = 0$	= 1.0 MHz, 24 V		115		1
Reverse Transfer Capacitance	C <sub>RSS</sub>	v <sub>DS</sub> = 24 v			75		1
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 15 V, I <sub>D</sub> = 7.0 A			12		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>				0.85		1
Gate-to-Source Charge	$Q_{GS}$	I <sub>D</sub> = 7.	0 A		1.9		1
Gate-to-Drain Charge	$Q_{GD}$				3.0		
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_D = 7.0 \text{ A}$			6.0		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>				0.8		1
Gate-to-Source Charge	$Q_{GS}$				1.85		
Gate-to-Drain Charge	$Q_{GD}$				3.0		
Gate Resistance	$R_{G}$				2.8		Ω
SWITCHING CHARACTERISTICS (Note 4)						,	
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS} = 10 \text{ V}, V_{DS} = 24 \text{ V},$ $I_D = 7.0 \text{ A}, R_G = 3.0 \Omega$			6.0		ns
Rise Time	t <sub>r</sub>				15		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				18		
Fall Time	t <sub>f</sub>				4.0		
DRAIN - SOURCE DIODE CHARACTERIST	ics						
Forward Diode Voltage	$V_{SD}$	$V_{GS} = 0 \text{ V},$ $I_{S} = 2.0 \text{ A}$ $T_{J} = 25^{\circ}\text{C}$ $T_{J} = 125^{\circ}\text{C}$			0.78	1.0	V
					0.63		
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V}$ $dI_{S}/dt = 100 \text{ A}/\mu\text{s}, I_{S} = 2.0 \text{ A}$			15		ns
Charge Time	t <sub>a</sub>				9.0		
							_
Discharge Time	t <sub>b</sub>	dl <sub>S</sub> /dt = 100 A/ <sub>į</sub>	us, I <sub>S</sub> = 2.0 A		6.0		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Pulse Test: pulse width  $\leq 300~\mu$ s, duty cycle  $\leq 2\%$ .

4. Switching characteristics are independent of operating junction temperatures.

### **TYPICAL PERFORMANCE CURVES**

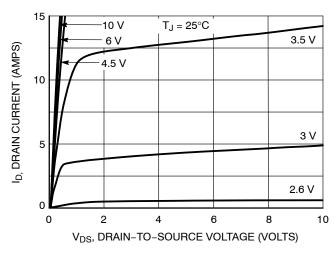
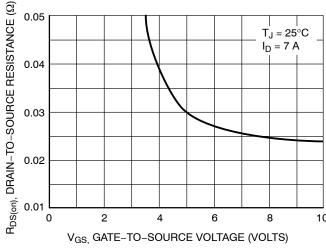


Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



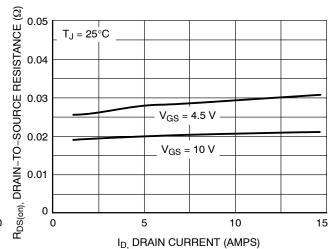
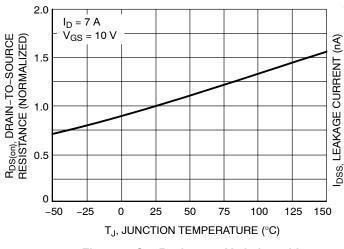


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



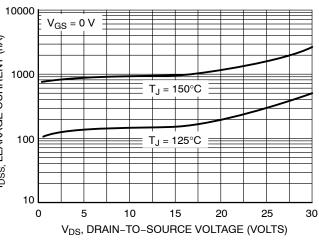
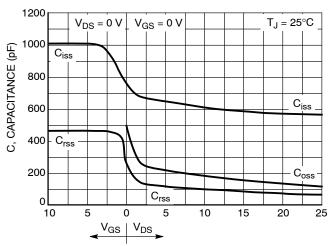


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL PERFORMANCE CURVES**



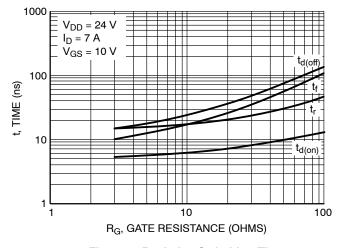
GATE-TO-SOURCE VOLTAGE (V) QT 6 QGS

→  $Q_{GD}$ I<sub>D</sub> = 7 A 2  $V_{DD} = 15 V$ Vgs (  $T_J = 25^{\circ}C$ 0 0 2 4 6 8 10 12 QG, TOTAL GATE CHARGE (nC)

GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge





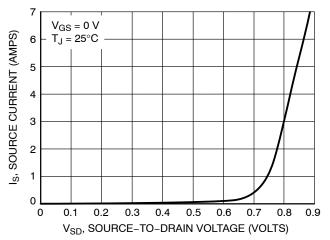
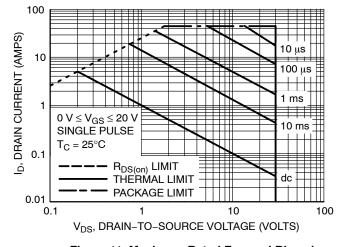


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current



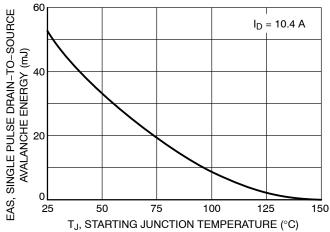


Figure 11. Maximum Rated Forward Biased Safe Operating Area

Figure 12. Maximum Avalanche Energy vs. **Starting Junction Temperature** 

### **TYPICAL PERFORMANCE CURVES**

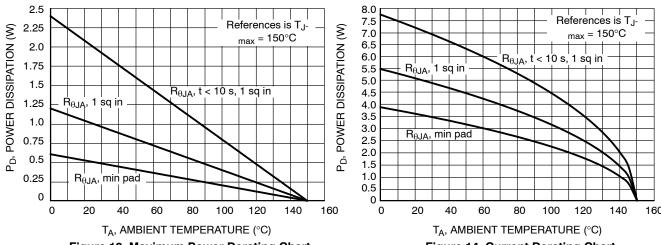


Figure 13. Maximum Power Derating Chart

Figure 14. Current Derating Chart

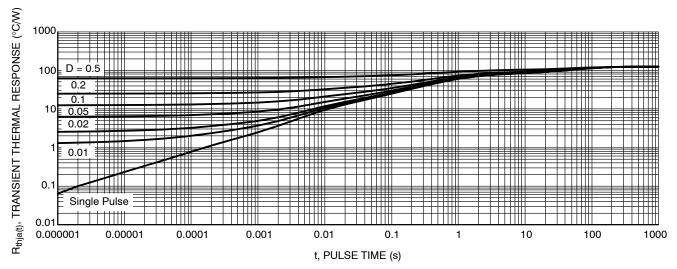


Figure 15. Thermal Response

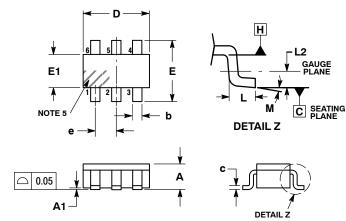
**Table 1. ORDERING INFORMATION** 

Part Number	Marking (XX)	Package	Shipping <sup>†</sup>
NTGS4141NT1	S4	TSOP-6	3000 / Tape & Reel
NTGS4141NT1G	S4	TSOP-6 (Pb-Free)	3000 / Tape & Reel
NVGS4141NT1G	VS4	TSOP-6 (Pb-Free)	3000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

### PACKAGE DIMENSIONS

### TSOP-6 CASE 318G-02 ISSUE V



#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETERS.
  MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH. MINIMUM
- MEATING MEAD THICKNESS INCLUES LEAD THISH. MINIMUM THICKNESS OF BASE MATERIAL. LEAD THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL. DIMENSIONS OF AND E1 DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS, MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.15 PER SIDE. DIMENSIONS D
- AND E1 ARE DETERMINED AT DATUM H.

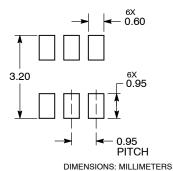
  5. PIN ONE INDICATOR MUST BE LOCATED IN THE INDICATED ZONE.

	MILLIMETERS			
DIM	MIN	NOM	MAX	
Α	0.90	1.00	1.10	
A1	0.01	0.06	0.10	
b	0.25	0.38	0.50	
С	0.10	0.18	0.26	
D	2.90	3.00	3.10	
E	2.50	2.75	3.00	
E1	1.30	1.50	1.70	
ø	0.85	0.95	1.05	
Ĺ	0.20	0.40	0.60	
L2	0.25 BSC			
М	0°	-	10°	

STYLE 1: PIN 1. DRAIN 2. DRAIN 3. GATE 4. SOURCE 5. DRAIN

6. DRAIN

### RECOMMENDED **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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